



- | | |
|--|--|
| <p>(51) International Patent Classification:
 G01R 31/02 (2006.01) G01R 19/165 (2006.01)
 G01R 31/307 (2006.01)</p> | <p>(81) Designated States (<i>unless otherwise indicated, for every kind of national protection available</i>): AE, AG, AL, AM, AO, AT, AU, AZ, BA, BB, BG, BH, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DO, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, GT, HN, HR, HU, ID, IL, IN, IS, JP, KE, KG, KM, KN, KP, KR, KZ, LA, LC, LK, LR, LS, LT, LU, LY, MA, MD, ME, MG, MK, MN, MW, MX, MY, MZ, NA, NG, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RS, RU, SC, SD, SE, SG, SK, SL, SM, ST, SV, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, ZA, ZM, ZW.</p> |
| <p>(21) International Application Number:
 PCT/IB2009/051356</p> | |
| <p>(22) International Filing Date:
 31 March 2009 (31.03.2009)</p> | |
| <p>(25) Filing Language: English</p> | |
| <p>(26) Publication Language: English</p> | |
| <p>(71) Applicant (<i>for all designated States except US</i>): FREESCALE SEMICONDUCTOR, INC. [US/US]; 6501 William Cannon Drive West, Austin, Texas 78735 (US).</p> | <p>(84) Designated States (<i>unless otherwise indicated, for every kind of regional protection available</i>): ARIPO (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HR, HU, IE, IS, IT, LT, LU, LV, MC, MK, MT, NL, NO, PL, PT, RO, SE, SI, SK, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).</p> |
| <p>(72) Inventors; and
 (75) Inventors/Applicants (<i>for US only</i>): FEFER, Yefim - Haim [IL/IL]; 1 Gadera Str., Apt. 24, 49724 Petah-Tikva (IL). SOFER, Sergey [IL/IL]; 4 Arthur Rubinstein Street, 75412 Reshon Letzion (IL). ZAPESCHINI, Boris [IL/IL]; Hameyasdim 1/9, 96224 Jerusalem (IL).</p> | <p>Declarations under Rule 4.17:</p> |

Declarations under Rule 4.17:

— *of inventorship (Rule 4.17(iv))*

[Continued on next page]

- (54) Title:** CONNECTION QUALITY VERIFICATION FOR INTEGRATED CIRCUIT TEST

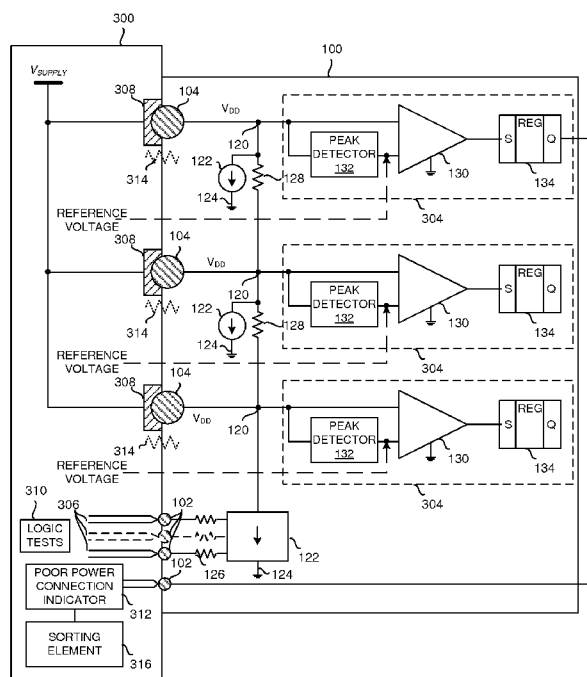


Fig. 3

- (57) Abstract:** An integrated circuit device 100 comprising a semiconductor die contained in a package. The integrated circuit device includes one or more internal connection verification modules 304 for asserting a poor connection signal for the test apparatus in response to a voltage difference between a voltage at a corresponding internal power supply node 120 and a reference voltage, the voltage difference being indicative of a poor connection of power supply to one of power supply terminals 104 on the package. The test apparatus 300, 400 can include an indicator 312 or a sorting element 316 for rejecting or accepting the integrated circuit device 100 in response to logic signals indicative of the presence or absence of a defect accompanied by non-assertion of the poor connection signal, and for processing the integrated circuit device 100 distinctively in response to assertion of the poor connection signal.

**Published:****(88) Date of publication of the international search report:**

30 June 2011

- *with international search report (Art. 21(3))*
- *before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments (Rule 48.2(h))*

INTERNATIONAL SEARCH REPORT

International application No.
PCT/IB2009/051356**A. CLASSIFICATION OF SUBJECT MATTER*****G01R 31/02(2006.01)i, G01R 31/307(2006.01)i, G01R 19/165(2006.01)i***

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

G01R 31/02; G01R 31/28; G01R 19/04; G01R 21/06; H01L 21/822

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Korean utility models and applications for utility models

Japanese utility models and applications for utility models

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)

eKOMPASS(KIPO internal) & Keywords: power, supply, connection, verification, reference

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	KR 10-2005-0014137 A (SAMSUNG ELECTRONICS CO., LTD.) 07 February 2005 see page 2, line 27 - page 4, line 53 and figures 1-3.	1-14
A	JP 2008-076356 A (FUJITSU LTD.) 03 April 2008 see paragraph [0005] - [0012]; claims 1-10 and figures 1-5.	1-14
A	US 2006-0217906 A1 (BARBARA, B. J. et al.) 28 September 2006 see paragraph [0017] - [0025] and figures 1-3.	1-14
A	US 05498972A A (HAULIN, TORD) 12 March 1996 see column 3, line 42 - column 6, line 5 and figures 1-5.	1-14

☐ Further documents are listed in the continuation of Box C.☒ See patent family annex.

* Special categories of cited documents:

"A" document defining the general state of the art which is not considered to be of particular relevance

"E" earlier application or patent but published on or after the international filing date

"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of citation or other special reason (as specified)

"O" document referring to an oral disclosure, use, exhibition or other means

"P" document published prior to the international filing date but later than the priority date claimed

"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

"Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art

"&" document member of the same patent family

Date of the actual completion of the international search

29 APRIL 2011 (29.04.2011)

Date of mailing of the international search report

02 MAY 2011 (02.05.2011)

Name and mailing address of the ISA/KR

Korean Intellectual Property Office
Government Complex-Daejeon, 189 Cheongsu-ro,
Seo-gu, Daejeon 302-701, Republic of Korea

Facsimile No. 82-42-472-7140

Authorized officer

LEE, SEON HEE

Telephone No. 82-42-481-8538



INTERNATIONAL SEARCH REPORT

Information on patent family members

International application No.

PCT/IB2009/051356

Patent document cited in search report	Publication date	Patent family member(s)	Publication date
KR 10-2005-0014137 A	07.02.2005	None	
JP 2008-076356 A	03.04.2008	EP 1903345 A1 US 2008-0106324 A1 US 2010-0052726 A1 US 2010-052726 A1 US 7635986 B2	26.03.2008 08.05.2008 04.03.2010 04.03.2010 22.12.2009
US 2006-0217906 A1	28.09.2006	EP 1869479 A2 JP 2008-545949 A JP 2008-545949 T KR 10-2007-0121010 A KR 2007-0121010 A US 2010-039739 A1 US 7609080 B2 WO 2006-102006 A2 WO 2006-102006 A3 WO 2006-102006 A3	26.12.2007 18.12.2008 18.12.2008 26.12.2007 26.12.2007 18.02.2010 27.10.2009 28.09.2006 09.04.2009 28.09.2006
US 05498972A A	12.03.1996	EP 0471399 A1 EP 0471399 B1	19.02.1992 24.05.1995